



7/19/2012

RELIABILITY MONITOR REPORT
FOR

MFN Silicon Gate 3 μ m CMOS (S3)

MAXIM Integrated Products

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Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX4582AUE+

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 7 QUANTITY: 80 FAILS: 1 FITS: 162

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 7/1/2011 and 6/30/2012 .

Process Information:

Process Description: MFN Silicon Gate 3µm CMOS (S3)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1042	MAX4582AUE+	135C	500 HRS	80	1	NO7BBA762BD
				Total:		1	
FAILURE RATE:		MTTF (YRS): 7		QUANTITY: 80		FAILS: 1	FITS: 16252.1